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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(Case No. 219.003-US)

In the Application of: **Yamada**

Serial No: **09/865,528**

Filed: **May 29, 2001**

Title: **Semiconductor Device Test Method and
Semiconductor Device Tester**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

) Group Art Unit: **2829**
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Michiko Saito
(person signing this certificate)

Michiko Saito
Signature

Date

SUBMISSION OF ENGLISH TRANSLATIONS

Dear Sir:

Attached hereto is an English translation of each of the following Japanese patent applications: JP H9-61142 and JP H8-5528, which were submitted in an Information Disclosure Statement dated March 17, 2004.

Respectfully submitted,

Neil A. Steinberg
Reg. No. 34,735
650-968-8079

Date: June 15, 2004